

SEM (Nova SEM)

주사전자현미경

Nova SEM is ultra-high resolution low vacuum SEM for nano-characterization and analysis. It features immersion lens electron optics in combination with novel low vacuum detector technology, giving uncompromised high vacuum and unprecedented low vacuum performance.

Model

FEI (Nova Nano SEM 200)

Specifications

- Accelerating voltage : 0.2 ~ 30 kV
- Image resolution : 1.0 nm
- Magnification : 25 ~ 1,000,000 X
- GSED (Gas Secondary Electron Detector)
- TLD (Through the Lens Detector)

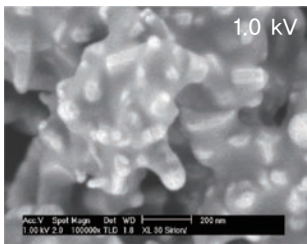
Applications

- STEM (Scanning Transmission Electron Microscopy) image
- Low voltage image



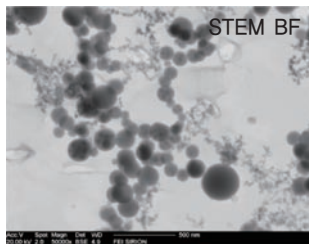
Location L5145 Tel.02-958-5972

Low voltage HR image



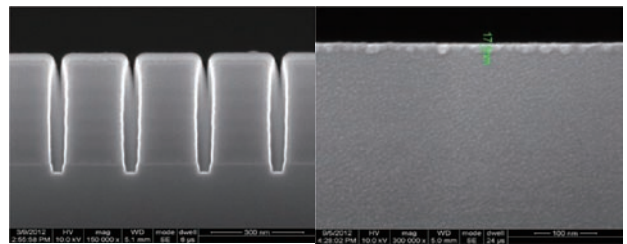
1.0 kV

STEM image

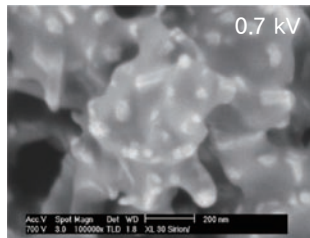


STEM BF

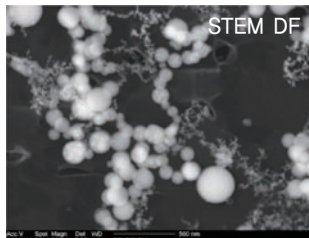
High voltage HR image



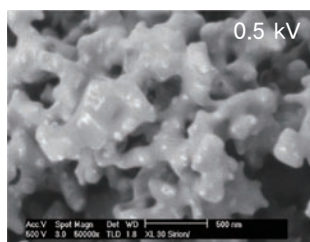
Ni-Cr electrode layer



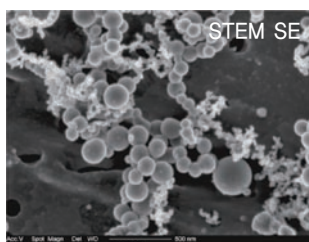
0.7 kV



STEM DF

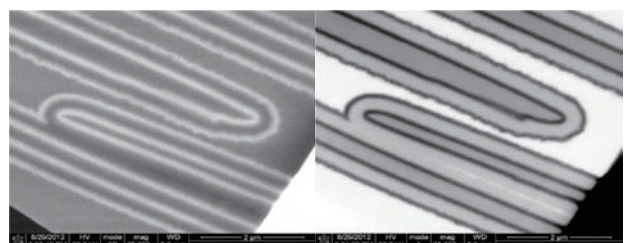


0.5 kV



STEM SE

SE & STEM image



SE STEM
FIB sample of pearlescent pigment